

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination LOCKYEAR ET AL.	
		Examiner Helen Rossoshek	Art Unit 2825	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,999,714 A	12-1999	Conn et al.	716/2
*	B	US-2003/0084411 A1	05-2003	Moskewicz et al.	716/3
*	C	US-2004/0210860 A1	10-2004	Ganai et al.	716/005
*	D	US-6,816,825 B1	11-2004	Ashar et al.	703/14
*	E	US-2004/0243964 A1	12-2004	McElvain et al.	716/012
*	F	US-7,020,861 B2	03-2006	Alpert et al.	716/6
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Guanghui et al., "Design error diagnosis based on verification techniques [logic IC design]", 16-19 Nov. 2003, Test Symposium, ATS 12th Asian, Page(s):474 - 477
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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